

High Speed IGBT3 Chip

Features:

- 650V Trench & Field Stop technology
- high speed switching series third generation
- low V_{CE(sat)}
- low EMI
- low turn-off losses
- positive temperature coefficient
- qualified according to JEDEC for target applications

Recommended for:

 discrete components and modules

Applications:

- uninterruptible power supplies
- welding converters
- converters with high switching frequency



Chip Type	V _{CE}	<i>I</i> _{Cn} ¹⁾	Die Size	Package
IGC31T65QE	650V	60A	6.67 x 4.69 mm ²	sawn on foil

¹⁾ nominal collector current at Tc = 100°C, not subject to production test - verified by design/characterization

Mechanical Parameters

Die size		6.67 x 4.69		
Emitter pad size		See chip drawing	mm ²	
Gate pad size		0.446 x 0.722		
Area total		31.28		
Thickness		70	μm	
Wafer size		200	mm	
Max.possible chips per wafer		842		
Passivation frontside		Photoimide		
Pad metal		3200 nm AlSiCu		
Backside metal		Ni Ag –system		
Die bond		Electrically conductive epoxy glue and soft solder		
Wire bond		Al, <500μm		
Reject ink dot size		∅ 0.65mm ; max 1.2mm		
Ctorage environment	for original and sealed MBB bags	Ambient atmosphere air, Temperature 17°C – 25°C, < 6 month		
Storage environment	for open MBB bags	Acc. to IEC62258-3: Atmosphere >99% Nitrogen or inert gas, Humidity <25%RH, Temperature 17°C – 25°C, < 6 month		

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Maximum Ratings

Parameter	Symbol	Value	Unit
Collector-Emitter voltage, $T_{\rm vj}$ =25 °C	V _{CE}	650	V
DC collector current, limited by $T_{\rm vjmax}$	Ic	1)	Α
Pulsed collector current, $t_{\rm p}$ limited by $T_{\rm vjmax}^{\ \ 2}$	I _{c,puls}	180	Α
Gate emitter voltage	V _{GE}	±20	V
Operating junction temperature	T _{vj}	-40 + 175	°C
Short circuit data ^{2) 3)} $V_{GE} = 15V$, $V_{CC} = 400V$, $T_{vj} = 150$ °C	tsc	5	μs

¹⁾ depending on thermal properties of assembly

Static Characteristics (tested on wafer), T_{vj} =25 °C

Parameter	Symbol	Conditions	Value			Unit
i diameter			min.	typ.	max.	
Collector-Emitter breakdown voltage	V _{(BR)CES}	$V_{\rm GE}$ =0V , $I_{\rm C}$ =2 mA	650			
Collector-Emitter saturation voltage	V _{CEsat}	V _{GE} =15V, I _C =60A	1.38	1.85	2.22	V
Gate-Emitter threshold voltage	$V_{GE(th)}$	$I_{\rm C}$ =1mA , $V_{\rm GE}$ = $V_{\rm CE}$	4.2	5.1	5.6	
Zero gate voltage collector current	I _{CES}	V _{CE} =650V , V _{GE} =0V			3	μA
Gate-Emitter leakage current	I _{GES}	V _{CE} =0V , V _{GE} =20V			150	nA
Integrated gate resistor	r_{G}			none		Ω

Electrical Characteristics (not subject to production test - verified by design / characterization)

Parameter	Symbol	Conditions	Value			11
Parameter			min.	typ.	max.	Unit
Collector-Emitter saturation voltage	V _{CEsat}	$V_{\rm GE}$ =15V, $I_{\rm C}$ =60A, $T_{\rm vj}$ =175 °C		2.25		V
Input capacitance	Cies	V_{CE} =25V, V_{GE} =0V, f =1MHz		3700		pF
Reverse transfer capacitance	C _{res}	$T_{\text{vj}} = 25 ^{\circ}\text{C}$		110] P'

Further Electrical Characteristic

Switching characteristics and thermal properties are depending strongly on module design and mounting technology and can therefore not be specified for a bare die.

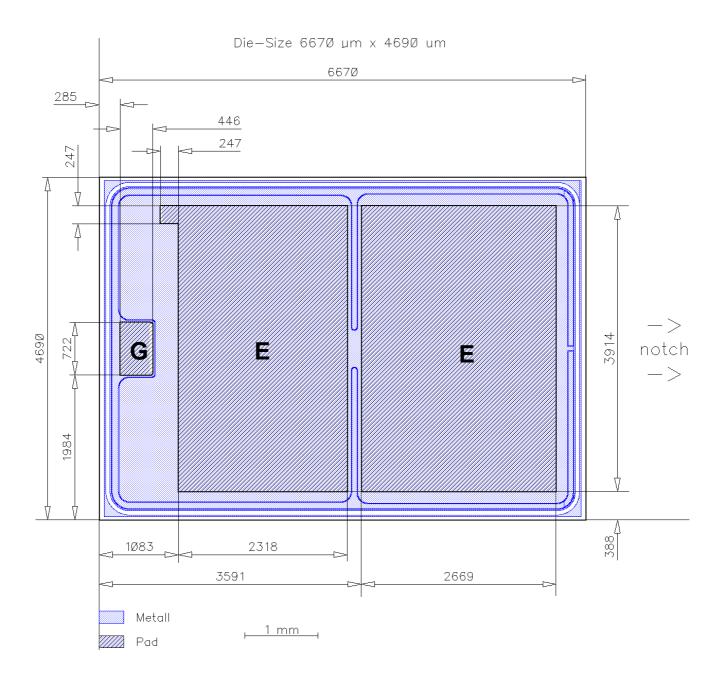
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²⁾ not subject to production test - verified by design/characterization

³⁾ allowed number of short circuits: <1000; time between short circuits: >1s.



Chip Drawing



E = Emitter

G = Gate



Description	
AQL 0,65 for visual inspection	according to failure catalogue

Electrostatic Discharge Sensitive Device according to MIL-STD 883

Revision History

Version	Subjects (major changes since last revision)	Date

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